


<b>Search Notes</b> 	<b>Application/Control No.</b> 10541906	<b>Applicant(s)/Patent Under Reexamination</b> FINCH ET AL.
	<b>Examiner</b> Barker, Matthew	<b>Art Unit</b> 3662

SEARCHED			
Class	Subclass	Date	Examiner
342	157.2.194,	12/21/2006	Hien Le
342	163,159-164	8/9/2007	Hien Ly
342	160	6/12/2008	MMB

SEARCH NOTES			
Search Notes		Date	Examiner
Inventor's name search		12/20/2006	Hien Ly
NPL search		12/20/2006	Hien Ly
Plus search		12/20/2006	Hien Ly
Text search		12/20/2006	Hien ly
NPL search (update)		8/8/2007	Hien ly
Text search (update)		8/8/2007	Hien Ly
342/104, 105, 109, 115, 194, 195, 161, 162, 164 - test search, see printoutx		6/12/2008	MMB
EAST text search - see printout		6/13/2008	MMB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner